

General Description

This planar stripe MOSFET has better characteristics, such as fast switching time, low on resistance, low gate charge and excellent avalanche characteristics. It is mainly suitable for DC/DC Converters and switching mode power supplies.

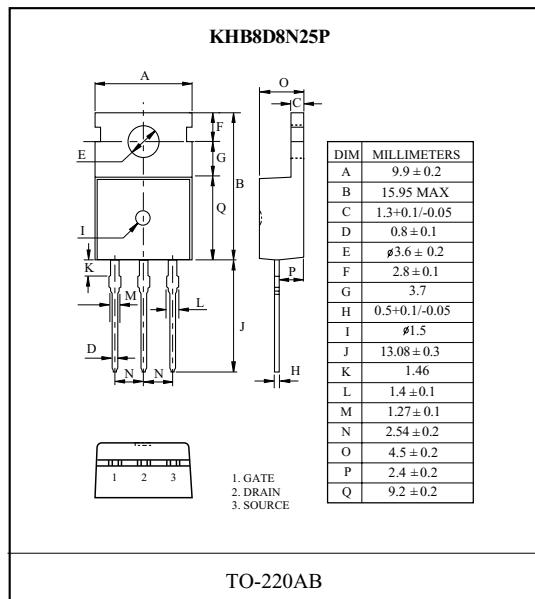
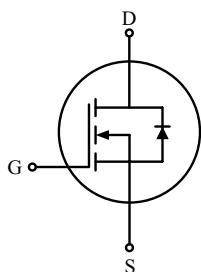
FEATURES

- $V_{DSS} = 250V$, $I_D = 8.8A$
- Drain-Source ON Resistance :
 $R_{DS(ON)} = 450m\Omega$ @ $V_{GS} = 10V$
- $Q_g(\text{typ.}) = 29.5nC$

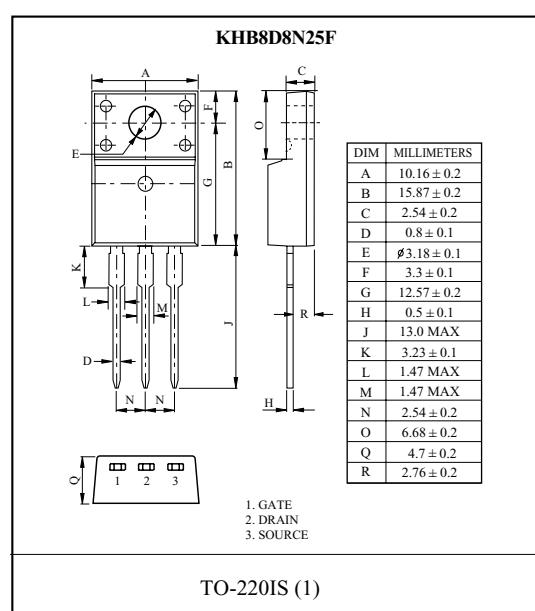
MAXIMUM RATING (Ta=25 °C)

CHARACTERISTIC	SYMBOL	RATING		UNIT
		KHB8D8N25P	KHB8D8N25F KHB8D8N25F2	
Drain-Source Voltage	V_{DSS}	250		V
Gate-Source Voltage	V_{GSS}	± 30		V
Drain Current @ $T_C = 25^\circ C$	I_D	8.8	8.8*	A
	I_{DP}	35.2	35.2*	
Single Pulsed Avalanche Energy (Note 2)	E_{AS}	285		mJ
Repetitive Avalanche Energy (Note 1)	E_{AR}	7.4		mJ
Peak Diode Recovery dv/dt (Note 3)	dv/dt	5.5		V/ns
Drain Power Dissipation	P_D	74	38	W
		0.59	0.3	W/°C
Maximum Junction Temperature	T_j	150		°C
Storage Temperature Range	T_{stg}	-55 ~ 150		°C
Thermal Characteristics				
Thermal Resistance, Junction-to-Case	R_{thJC}	1.69	3.29	°C/W
Thermal Resistance, Junction-to-Ambient	R_{thJA}	62.5	62.5	°C/W

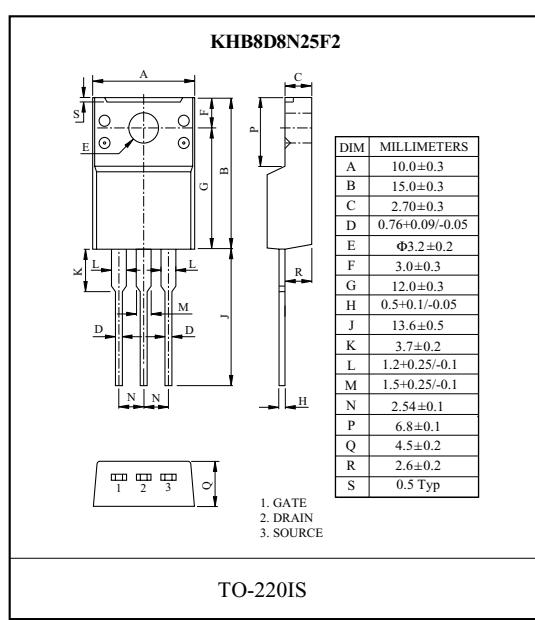
* : Drain current limited by maximum junction temperature.

PIN CONNECTION

TO-220AB



TO-220IS (1)



TO-220IS

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ELECTRICAL CHARACTERISTICS (Ta=25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	BV _{DSS}	I _D =250μA, V _{GS} =0V	250	-	-	V
Breakdown Voltage Temperature Coefficient	ΔBV _{DSS} /ΔT _j	I _D =250μA, Referenced to 25 °C	-	0.27	-	V/°C
Gate Threshold Voltage	V _{th}	V _{DS} =V _{GS} , I _D =250μA	2.0	-	4.0	V
Drain Cut-off Current	I _{DSS}	V _{DS} =250V, V _{GS} =0V,	-	-	10	μA
Gate Leakage Current	I _{GSS}	V _{GS} =±30V, V _{DS} =0V	-	-	±100	nA
Drain-Source ON Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =4.4A	-	360	450	mΩ
Forward Transconductance	g _{FS}	V _{DS} =40V, I _D =4.4A (Note4)	-	7.6	-	S
Dynamic						
Total Gate Charge	Q _g	V _{DS} =200V, I _D =8.8A V _{GS} =10V (Note4,5)	-	29.5	36.5	nC
Gate-Source Charge	Q _{gs}		-	3.8	-	
Gate-Drain Charge	Q _{gd}		-	14.5	-	
Turn-on Delay time	t _{d(on)}	V _{DD} =125V R _G =25 Ω I _D =8.8A (Note4,5)	-	14.5	39	ns
Turn-on Rise time	t _r		-	69	148	
Turn-off Delay time	t _{d(off)}		-	73	156	
Turn-off Fall time	t _f		-	60	130	
Input Capacitance	C _{iss}	V _{DS} =25V, V _{GS} =0V, f=1.0MHz	-	622	810	pF
Output Capacitance	C _{oss}		-	117	152	
Reverse Transfer Capacitance	C _{rss}		-	37	48	
Source-Drain Diode Ratings						
Continuous Source Current	I _S	V _{GS} <V _{th}	-	-	8.8	A
Pulsed Source Current	I _{SP}		-	-	35.2	
Diode Forward Voltage	V _{SD}	I _S =8.8A, V _{GS} =0V	-	-	1.5	V
Reverse Recovery Time	t _{rr}	I _S =8.8A, V _{GS} =0V, dI _S /dt=100A/μs	-	170	-	ns
Reverse Recovery Charge	Q _{rr}		-	0.91	-	μC

Note 1) Repetitvity rating : Pulse width limited by junction temperature.

Note 2) L = 5.9mH, I_S=8.8A, V_{DD}=50V, R_G = 25 Ω , Starting T_j = 25 °C.

Note 3) I_S ≤ 8.8A, dI/dt ≤ 300A/μs, V_{DD} ≤ BV_{DSS}, Starting T_j = 25 °C.

Note 4) Pulse Test : Pulse width ≤ 300μs, Duty Cycle ≤ 2%.

Note 5) Essentially independent of operating temperature.

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Fig1. I_D - V_{DS}

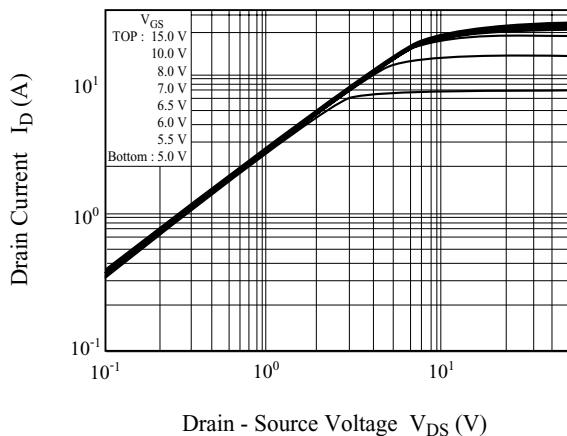


Fig2. I_D - V_{GS}

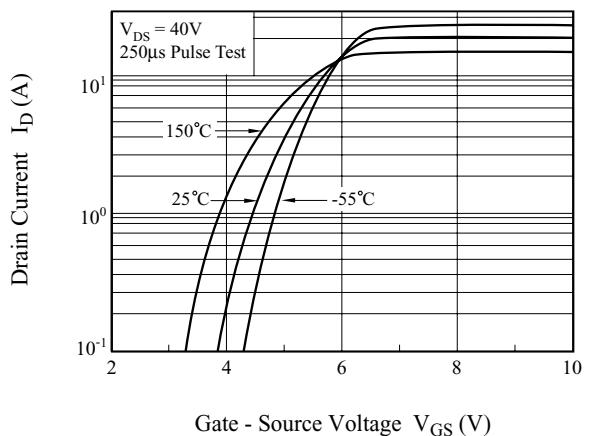


Fig3. BV_{DSS} - T_j

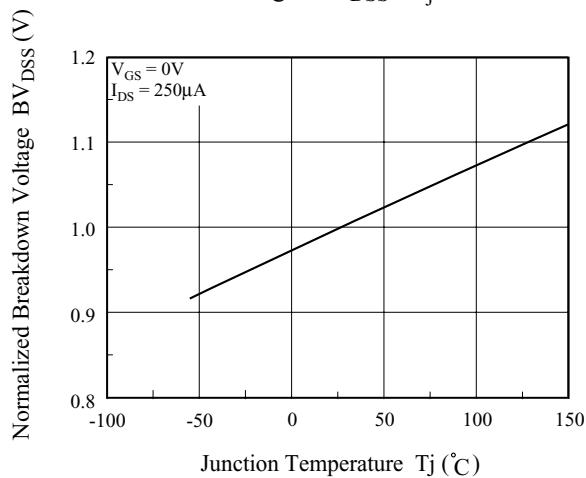


Fig4. $R_{DS(ON)}$ - I_D

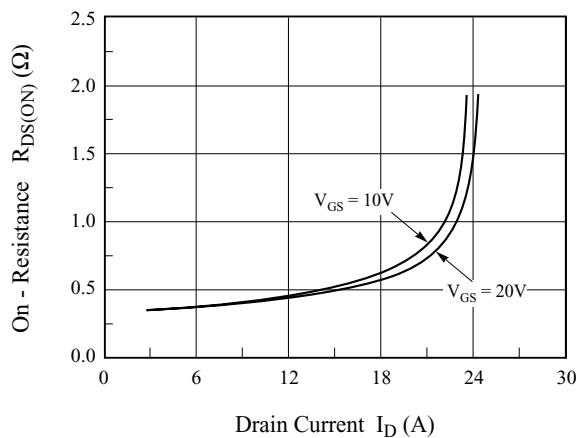


Fig5. I_S - V_{SD}

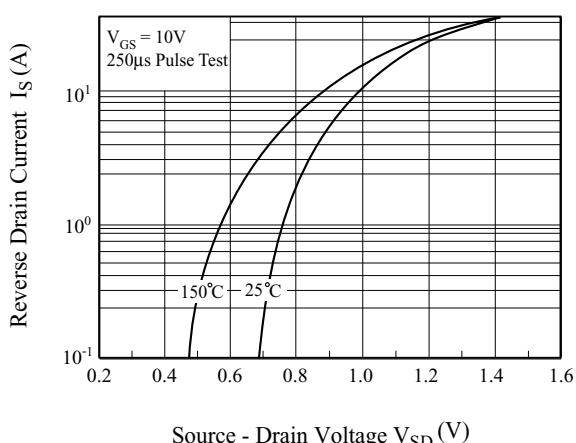
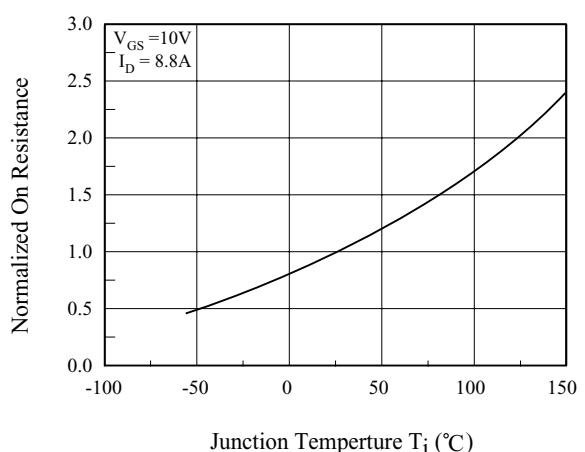


Fig6. $R_{DS(ON)}$ - T_j



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Fig7. C - V_{DS}

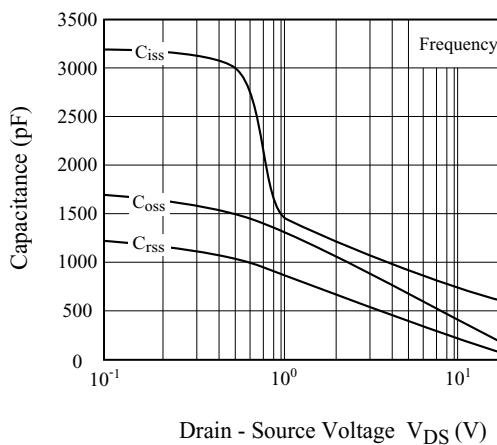


Fig8. Q_g- V_{GS}

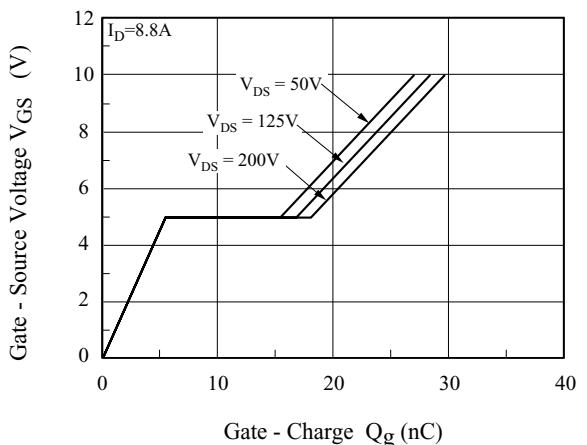


Fig9. Safe Operation Area

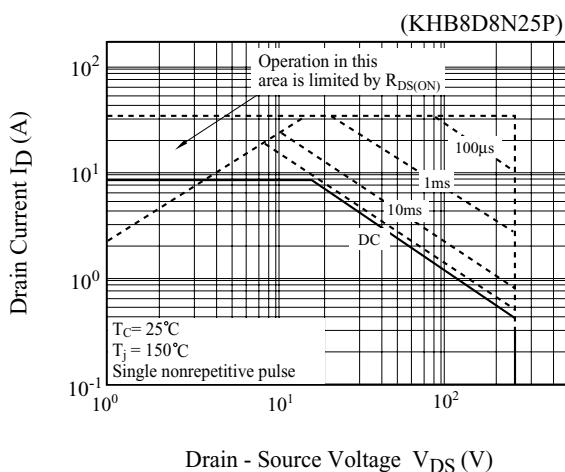


Fig10. Safe Operation Area

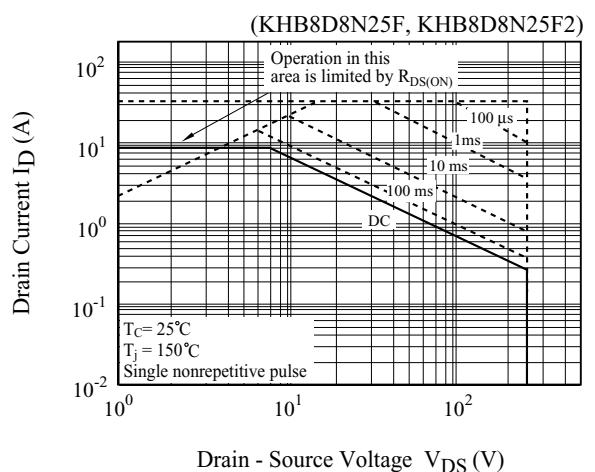
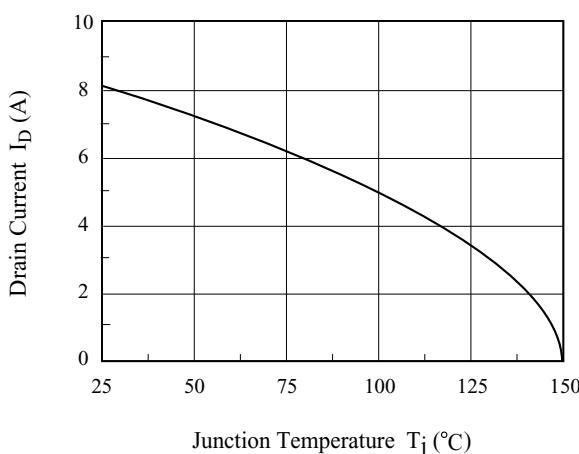


Fig11. I_D - T_j



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Fig12. Transient Thermal Response Curve

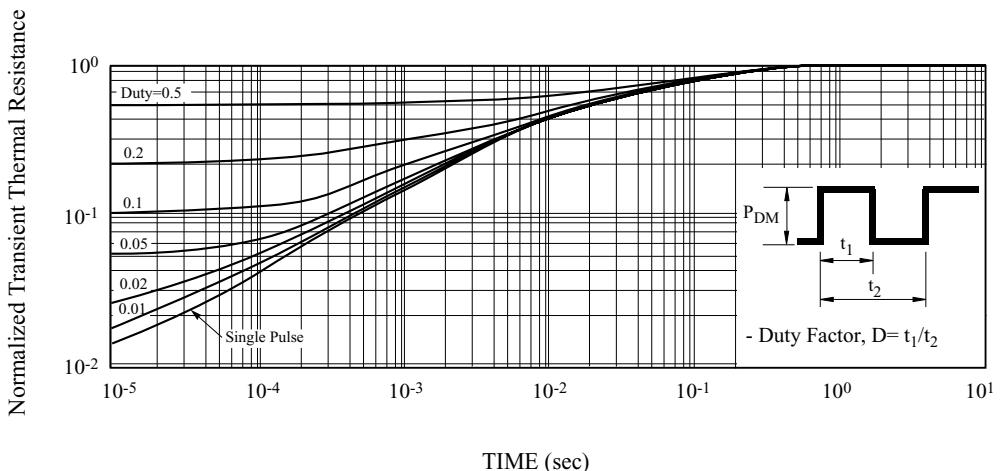
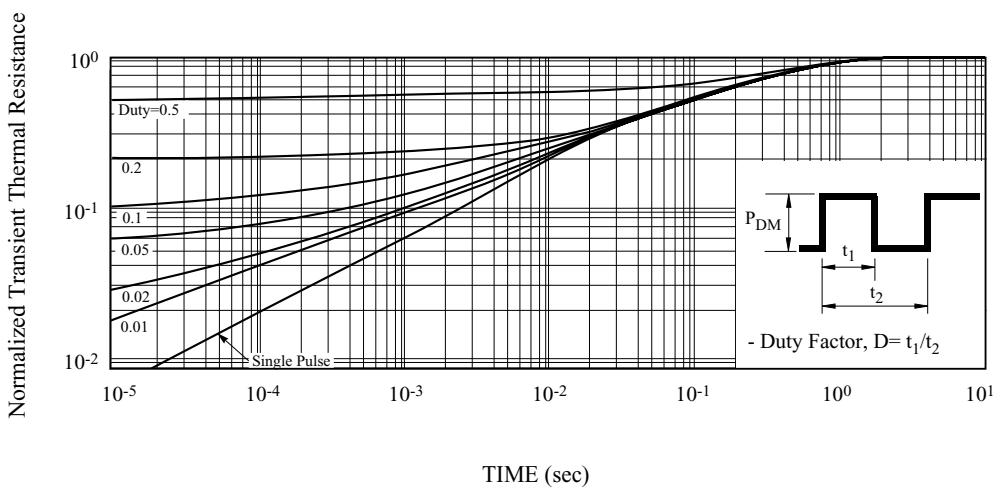


Fig13. Transient Thermal Response Curve



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Fig14. Gate Charge

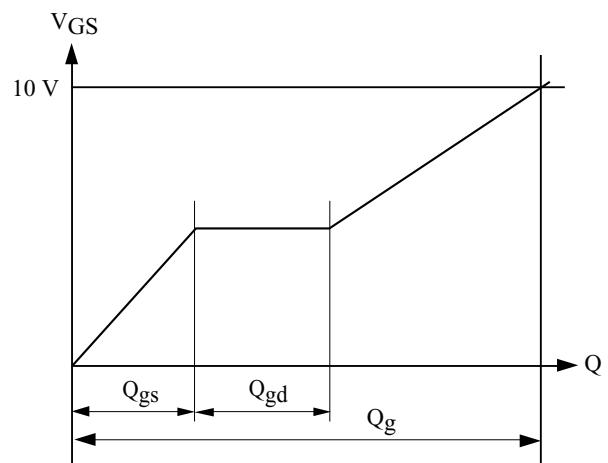
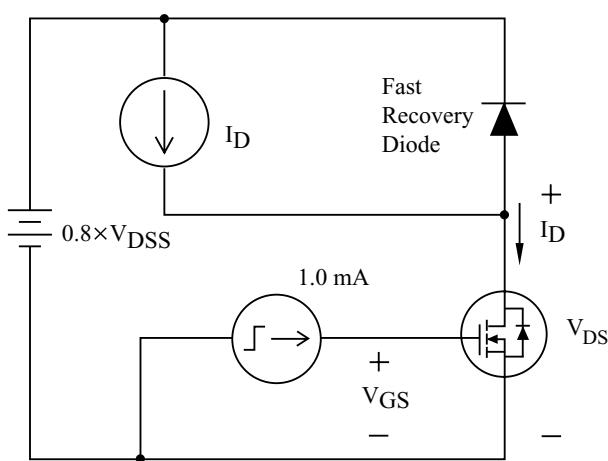
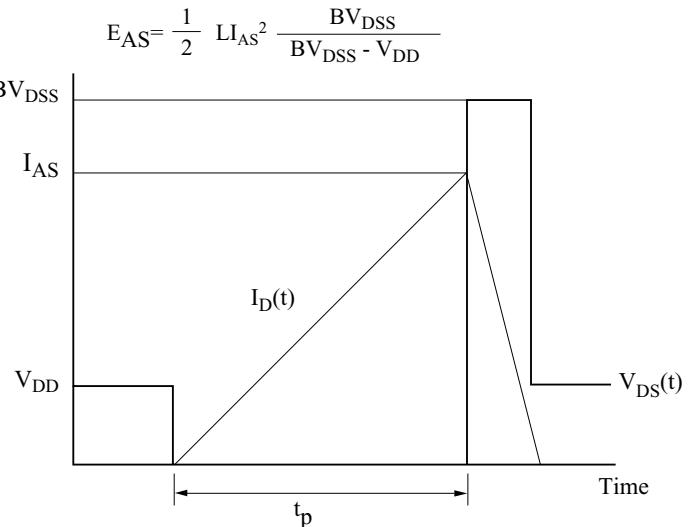
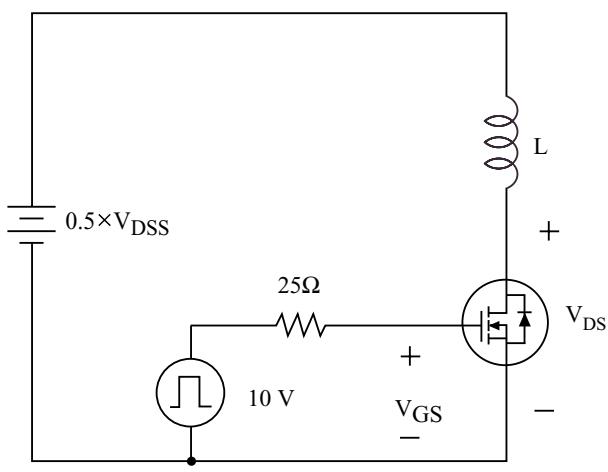


Fig15. Single Pulsed Avalanche Energy



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Fig16. Resistive Load Switching

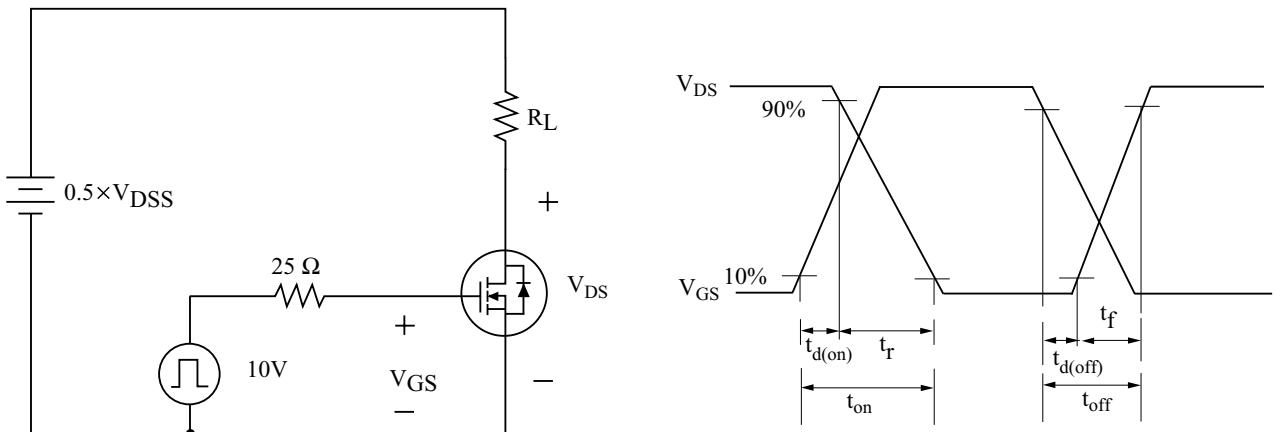


Fig17. Source - Drain Diode Reverse Recovery and dv /dt

